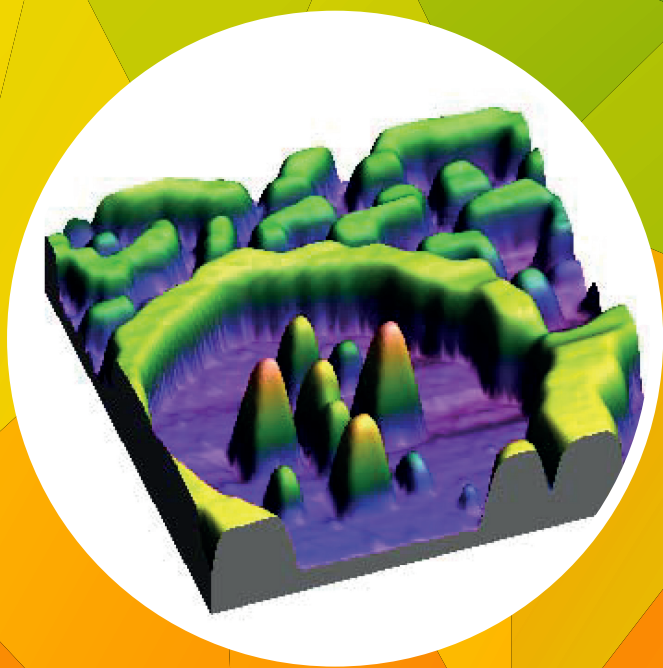


AFM15

AFM BEYOND IMAGING

NANOSCALE CHARACTERIZATION OF FUNCTIONAL MATERIALS



9:00 h

Xavier Obradors

(Institut de Ciència de Materials de Barcelona-ICMAB-CSIC)

Opening and introduction

9:10 h

Neus Domingo

(Institut Català de Nanociència i Nanotecnologia-ICN2)

"Electromechanical response at the nanoscale: from violins to electrical drums"

9:50 h

Andres Gómez

(Institut de Ciència de Materials de Barcelona-ICMAB-CSIC)

"Current Sensing AFM: Electrical Characterization of Materials"

10:30 h

Elena Bailo

(WITec GmbH, Barcelona)

"3D Fast Raman Imaging Meets SPM"

11:10 h

Coffe break

11:40

Alvaro San Paulo

(Instituto de Microelectrónica de Madrid-IMM)

"Quantitative Nanomechanical Mapping Of Breast Cancer Cells By Peak Force Tapping Atomic Force Microscopy"

12:20

Pedro J. de Pablo

(Universidad Autónoma de Madrid-UAM)

"Physical virology with Atomic Force Microscopy"

13:00

Benjamín L. Holmes

(JPK Instruments AG)

"High-speed AFM imaging of soft and biological matter in liquids: challenges and results"

13:40

Lunch (not included)

15:40

Agustina Asenjo

(Instituto de Ciencia de Materiales de Madrid-ICMM)

"Nanoscale magnetism by Magnetic Force Microscopy"

16:20

Sascha Sadewasser

(Iberian Nanotechnology Laboratory-INL, Braga)

"Kelvin probe force microscopy: From atomic scale imaging to application on solar cell materials"

17:00

Gabriel Gomila

(Universitat de Barcelona, Institut de Bioenginyeria de Catalunya-UB-IBEC)

"Quantitative electrostatic force microscopy for dielectric measurements in material science and biology"

17:40-19:00

Poster session

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